Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10734472	CHARETTE, MARC F.
Examiner	Art Unit
Wang, Chang-Yu	1649

SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES				
Search Notes	Date	Examiner		
sequence search: SEQ ID NO:2 and aa. 30-431, aa. 30-292, 292-330, 292-431of SEQ ID NO:21. See sequence search results in SCORE (updated)	12/4/07	CYW		
EAST, STN: search strategy attached (updated)	12/4/07	CYW		
Inventor name search: EAST, STN, PALM (updated)	12/4/07	CYW		
PLUS search from STIC. See search results in eDAN (11/13/07)	12/4/07	CYW		

	INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner		

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